

## Using Brewster Angle for Measuring Microwave Material Parameters of Bi-Isotropic and Chiral Media

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*A.H. Sihvola and I.V. Lindell. "Using Brewster Angle for Measuring Microwave Material Parameters of Bi-Isotropic and Chiral Media." 1992 MTT-S International Microwave Symposium Digest 92.2 (1992 Vol. II [MWSYM]): 1135-1138.*

This contribution focuses on the retrieval of chiral and nonreciprocal material parameters of bi-isotropic media. Using the generalized Fresnel reflection coefficients, that the authors have recently derived for general bi-isotropic media, a reflection method is suggested for determining the materials parameters of an unknown material sample. The sample needs to be thick enough for no transmission and multiple reflection effects to occur, and it should have one planar surface extending widely enough to cover the beam of the measuring antenna beam.

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